# MSKSEMI















**ESD** 

TVS

TSS

MOV

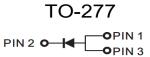
GDT

**PLED** 

# Broduct data sheet







#### ■ Features

- · Low forward voltage drop.
- Excellent high temperature stability.
- Fast switching capability.
- Suffix "G" indicates Halogen-free part, ex.CP10S45SG.
- Lead-free parts meet environmental standards of MIL-STD-19500/228

#### ■ Mechanical data

- Epoxy: UL94-V0 rated flame retardant.
- Case: Molded plastic, TO-277.
- Lead: Solder plated, solderable per MIL-STD-750, Method 2026.
- Polarity: Indicated by cathode band.
- Mounting Position : Any.
- Weight: Approximated 0.093 grams.

# MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

For capacitive load, derate current by 20%.

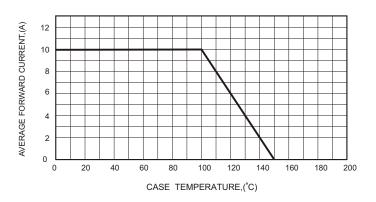
P/N(MARK)	SB1080L	UNITS
Maximum Recurrent Peak Reverse Voltage	80	V
Maximum RMS Voltage	56	V
Maximum DC Blocking Voltage	80	V
Maximum Average Forward Rectified Current		
See Fig. 1	10.0	Α
Peak Forward Surge Current, 8.3 ms single half sine-wave		
superimposed on rated load (JEDEC method)	150	Α
Maximum Instantaneous Forward Voltage at 10.0A	0.7	V
Maximum DC Reverse Current Ta=25°C	100	μА
at Rated DC Blocking Voltage Ta=125°C	20	mA
Typical Junction Capacitance (Note1)	500	pF
Typical Thermal Resistance R JA (Note 2)	60	°C/W
Operating Temperature Range T <sub>J</sub>	55 to +150 -	°C
Storage Temperature Range TstG	-55 t <del>o</del> +150	°C

Note: 1.FR-4 PCB, 2oz.Copper.
2.Polymide PCB, 2oz.Copper.Cathode pad dimensions 18.8mm x 14.4mm.Anode pad dimensions 5.6mm x 14.4mm.

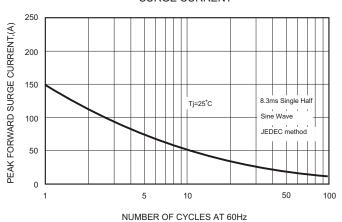


## RATING AND VHARACTERISTIC CURVES

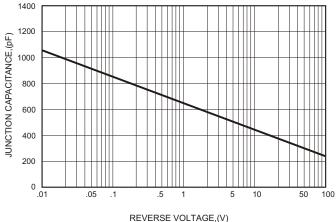
#### FIG.1-TYPICAL FORWARD CURRENT DERATING CURVE



#### FIG.3-MAXIMUM NON-REPETITIVE FORWARD SURGE CURRENT



# FIG.4-TYPICAL JUNCTION CAPACITANCE



#### FIG.2-TYPICAL FORWARD

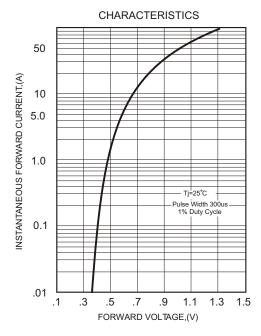
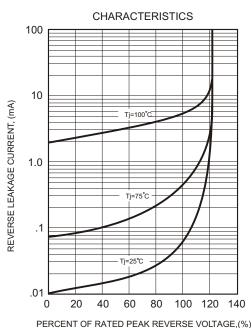


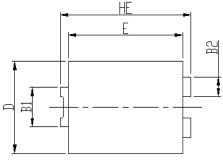
FIG.5 - TYPICAL REVERSE



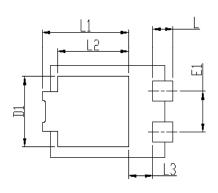
Semiconductor





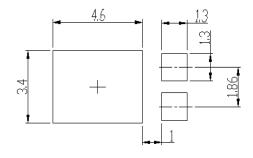






	Unit: mm		Linit: inch	
DIM	Unit: mm		Unit: inch	
Dilvi	MIN	MAX	MIN	MAX
HE	6.4	6.6	0.252	0.260
Е	5.6	5.8	0.220	0.228
D	4.1	4.3	0.161	0.169
B1	1.7	1.9	0.067	0.075
B2	0.8	1	0.031	0.039
Α	1.05	1.2	0.041	0.047
С	0.3	0.4	0.012	0.016
L	0.85	1.1	0.033	0.043
L1	4.2	4.4	0.165	0.173
L2	3.52 Typ.		0.139 Typ.	
L3	1.1	1.4	0.043	0.055
D1	3	3.3	0.118	0.130
E1	1.86 Typ.		0.073 Typ.	

T0-277 Suggested Pad Layout



### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance ± 0.05mm.
- 3. The pad layout is for reference purposes only.

### **REEL SPECIFICATION**

P/N	PKG	QTY
SB1080L	TO-277	5000



# Attention

- Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.
- MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specificationsof any andall MSKSEMI Semiconductor products described orcontained herein.
- Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- MSKSEMI Semiconductor. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possiblethat these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuitsfor safedesign, redundant design, and structural design.
- In the event that any or all MSKSEMI Semiconductor products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringementsof intellectual property rights or other rightsof third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor product that you intend to use.